

# Search Notes



Application/Control No.

10/719,346

Examiner

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Applicant(s)/Patent under Reexamination

CHEN, CHIA-TEH

Art Unit

3746

## SEARCHED

Class	Subclass	Date	Examiner
417	423.15	11/5/05	ES
	423.3		
	423.5		
416	5		
	99		
	100		
	110		
	123		
	130	11/7/05	ES

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See Int. Search		11/7/05	ES
East			

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
417-hey 416-verdier	11/4/05	ES
See East txt	11/4/05	ES